

General Description

The CH70N04A combines advanced trench MOSFET technology with a low resistance package to provide extremely low $R_{DS(ON)}$. This device is ideal for load switch and battery protection applications.

Features

- Advance high cell density Trench technology
- Low $R_{DS(ON)}$ to minimize conductive loss
- Low Gate Charge for fast switching
- Low Thermal resistance

Application

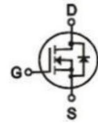
- MB/VGA Vcore
- SMPS 2nd Synchronous Rectifier
- POL application
- BLDC Motor driver

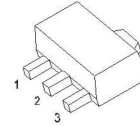
Ordering Information:

Part NO.	CH70N04A
Marking	CH70N04A
Packing Information	REEL TAPE
Basic ordering unit (pcs)	1000

Absolute Maximum Ratings ($T_c = 25^\circ\text{C}$)

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	V_{DS}	40	V
Gate-Source Voltage	V_{GS}	20	V
Continuous Drain Current	$I_D@TC=25^\circ\text{C}$	70	A
	$I_D@TC=75^\circ\text{C}$	50	A
	$I_D@TC=100^\circ\text{C}$	36	A
Pulsed Drain Current (1)	I_{DM}	240	A
Total Power Dissipation($TC=25^\circ\text{C}$)	$P_D@TC=25^\circ\text{C}$	48	W
Total Power Dissipation($TA=25^\circ\text{C}$)	$P_D@TA=25^\circ\text{C}$	2.0	W
Operating Junction Temperature	T_J	-55 to 150	$^\circ\text{C}$
Storage Temperature	T_{STG}	-55 to 150	$^\circ\text{C}$
Single Pulse Avalanche Energy@L=0.1mH	E_{AS}	72	mJ
Avalanche Current@L=0.1mH	I_{AS}	55	A

Product Summary

 $V_{DS} = 40\text{V}$
 $I_D = 70\text{A}$
 $R_{DS(ON)}$ Typ = $8.5\text{m}\Omega$
 @ $V_{GS} = 10\text{V}$
SOT-89-3L

 1. GATE
 2. DRAIN
 3. SOURCE


•Thermal resistance

Parameter	Symbol	Min.	Typ.	Max.	Unit
Thermal resistance, junction - case	R_{thJC}	-	-	2.6	$^{\circ}C/W$
Thermal resistance, junction - ambient	R_{thJA}	-	-	62.5	$^{\circ}C/W$
Soldering temperature, wavesoldering for 10s	T_{sold}	-	-	265	$^{\circ}C$

•Electronic Characteristics

Parameter	Symbol	Condition	Min.	Typ	Max.	Unit
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS}=0V, I_D=250\mu A$	40			V
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{GS}=V_{DS}, I_D=250\mu A$	1	1.5	2.0	V
Drain-Source Leakage Current	I_{DSS}	$V_{DS}=20V, V_{GS}=0V$			1.0	μA
Gate- Source Leakage Current	I_{GSS}	$V_{GS}=\pm 12V, V_{DS}=0V$			± 100	nA
Static Drain-source On Resistance	$R_{DS(ON)}$	$V_{GS}=10V, I_D=20A$		8.5	10	m Ω
		$V_{GS}=4.5V, I_D=10A$		11	14	m Ω
Forward Transconductance	g_{FS}	$V_{DS}=15V, I_D=10A$		16		S
Source-drain voltage	V_{SD}	$I_S=20A$			1.50	V

•Electronic Characteristics

Parameter	Symbol	Condition	Min.	Typ	Max.	Unit
Input capacitance	C_{iss}	f = 1MHz	-	3177	-	pF
Output capacitance	C_{oss}		-	150	-	
Reverse transfer capacitance	C_{rss}		-	133	-	

•Gate Charge characteristics($T_a = 25^{\circ}C$)

Parameter	Symbol	Condition	Min.	Typ	Max.	Unit
Total gate charge	Q_g	$V_{DS}=20V$ $I_D=20A$ $V_{GS}=0V$ TO 10V	-	45	-	nC
Gate - Source charge	Q_{gs}		-	8	-	
Gate - Drain charge	Q_{gd}		-	11	-	

- Notes:
1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature.
 2. E_{AS} condition: Starting $T_J=25^{\circ}C$, $V_{DS}=20V$, $V_G=10V$, $R_G=25\Omega$, $L=0.5mH$, $I_{AS}=17A$
 3. Pulse Test: Pulse Width $\leq 300\mu s$, Duty Cycle $\leq 0.5\%$.

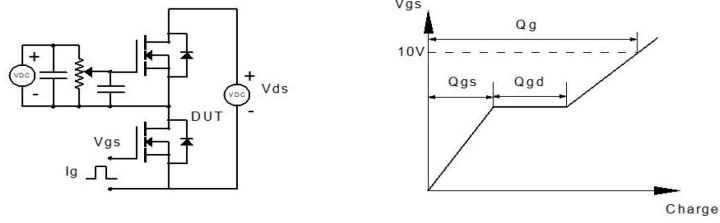


Figure 1: Gate Charge Test Circuit & Waveform

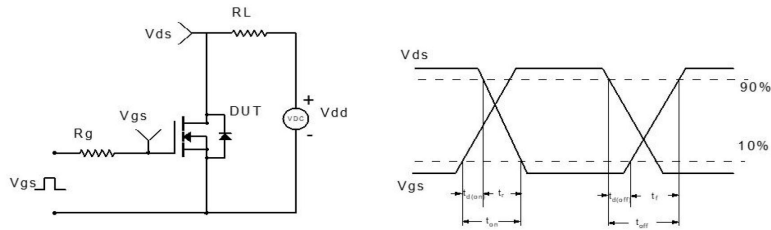


Figure 2: Resistive Switching Test Circuit & Waveform

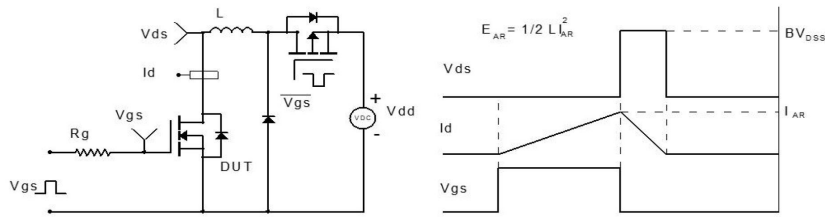


Figure 3: Unclamped Inductive Switching Test Circuit & Waveform

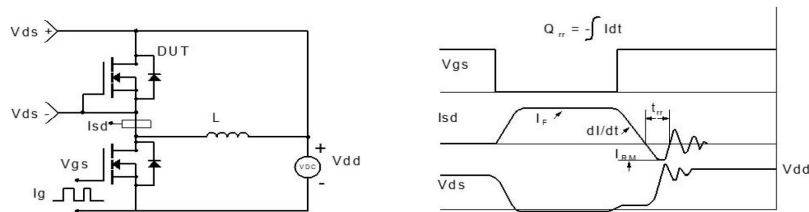
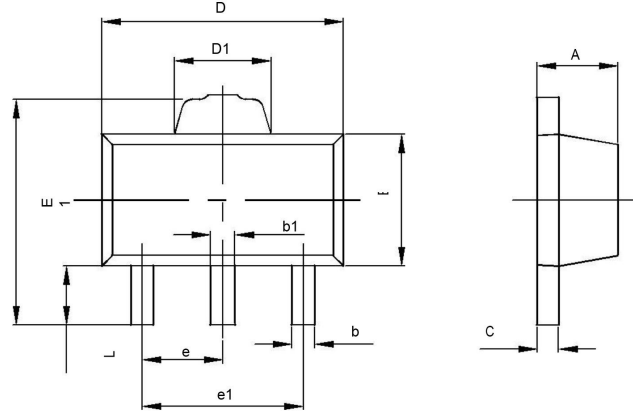


Figure 4: Diode Recovery Test Circuit & Waveform

SOT-89-3L PACKAGE OUTLINE DIMENSIONS


Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min	Max	Min	Max
A	1.400	1.600	0.055	0.063
b	0.320	0.520	0.013	0.020
b1	0.360	0.560	0.014	0.022
c	0.350	0.440	0.014	0.017
D	4.400	4.600	0.173	0.181
D1	1.400	1.800	0.055	0.071
E	2.300	2.600	0.091	0.102
E1	3.940	4.250	0.155	0.167
e	1.500TYP		0.060TYP	
e1	2.900	3.100	0.114	0.122
L	0.900	1.100	0.035	0.043